

Notice of References Cited

Application/Control No.

09/404,122

Applicant(s)/Patent Under
Reexamination
YAHIL ET AL.

Examiner

Ayal I. Sharon

Art Unit

2123

Page 1 of 5

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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Ayal I. Sharon

Art Unit

2123

Page 2 of 5

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YAHIL ET AL.

Examiner

Ayal I. Sharon

Art Unit

2123

Page 3 of 5

U.S. PATENT DOCUMENTS

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Application/Control No.

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YAHIL ET AL.

Examiner

Ayal I. Sharon

Art Unit

2123

Page 4 of 5

U.S. PATENT DOCUMENTS

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Page 5 of 5

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